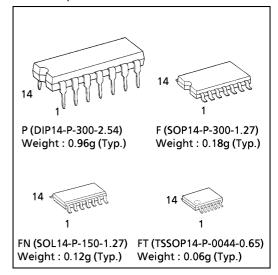
TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC4001BP, TC4001BF, TC4001BFN, TC4001BFT

TC4001B QUAD 2 INPUT NOR GATE

The TC4001B is 2-input positive NOR gate, respectively. Since the outputs of these gates are epuipped with the buffers, the input / output transmission characteristics have been improved and the variation of transmission time due to an increase in the load capacity is kept minimum.

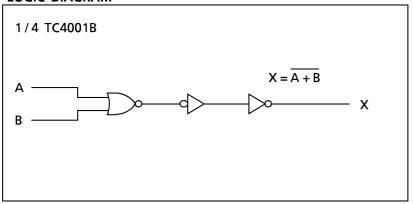
(Note) The JEDEC SOP (FN) is not available in Japan.



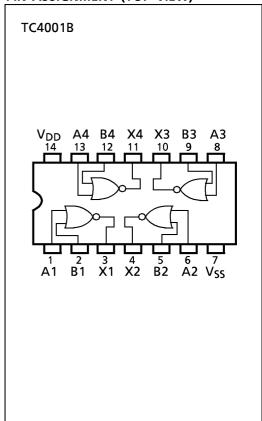
MAXIMUM RATINGS

CHARACTERISTIC	SYMBOL	RATING	UNIT
DC Supply Voltage	V_{DD}	$V_{SS} - 0.5 \sim V_{SS} + 20$	V
Input Voltage	VIN	$V_{SS} - 0.5 \sim V_{DD} + 0.5$	٧
Output Voltage	V _{OUT}	$V_{SS} - 0.5 \sim V_{DD} + 0.5$	V
DC Input Current	I _{IN}	± 10	mA
Power Dissipation	P _D	300 (DIP) / 180 (SOIC)	mW
Operating Temperature Range	T _{opr}	- 40~85	°C
Storage Temperature Range	T _{stg}	- 65~150	°C

LOGIC DIAGRAM



PIN ASSIGNMENT (TOP VIEW)



2001-05-17

1

RECOMMENDED OPERATING CONDITIONS $(V_{SS} = 0V)$

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
DC Supply Voltage	V_{DD}		3	-	18	V
Input Voltage	V _{IN}		0		V_{DD}	V

STATIC ELECTRICAL CHARACTERISTICS ($V_{SS} = 0V$)

CHARACTERISTIC		SYM-	TEST CONDITION	V-	– 40°C			25°C		85°C		UNIT
СПАКА	CIERISTIC	BOL	TEST CONDITION	(V)	MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.	JUNIT
High-Leve Output V		V _{OH}	$ I_{OUT} < 1\mu A$ $V_{IN} = V_{SS}, V_{DD}$	5 10 15	4.95 9.95 14.95	_ _ _	4.95 9.95 14.95	5.00 10.00 15.00	_ _ _	4.95 9.95 14.95	_ _ _	V
Low-Leve Output V		V _{OL}	$\begin{aligned} I_{OUT} < 1\mu A \\ V_{IN} = V_{SS}, \ V_{DD} \end{aligned}$	5 10 15		0.05 0.05 0.05		0.00 0.00 0.00	0.05 0.05 0.05		0.05 0.05 0.05	V
Output H	ligh Current	І _{он}	$V_{OH} = 4.6V$ $V_{OH} = 2.5V$ $V_{OH} = 9.5V$ $V_{OH} = 13.5V$ $V_{IN} = V_{SS}$	5 10 15	- 0.61 - 2.50 - 1.50 - 4.00		- 0.51 - 2.10 - 1.30 - 3.40	- 2.2		- 0.42 - 1.70 - 1.10 - 2.80	_ _ _	
Output L	ow Current	I _{OL}	$V_{OL} = 0.4V$ $V_{OL} = 0.5V$ $V_{OL} = 1.5V$ $V_{IN} = V_{SS}, V_{DD}$	5 10 15	0.61 1.50 4.00		0.51 1.30 3.40	1.2 3.2 12.0	_ _ _	0.42 1.10 2.80	_ _ _	- mA
Input Hig	h Voltage	V _{IH}	$V_{OUT} = 0.5V$ $V_{OUT} = 1.0V$ $V_{OUT} = 1.5V$ $ I_{OUT} < 1\mu A$	5 10 15	3.5 7.0 11.0	_ _ _	3.5 7.0 11.0	2.75 5.50 8.25	_ _ _	3.5 7.0 11.0	_ _ _	V
Input Lov	v Voltage	V _{IL}	$V_{OUT} = 4.5V$ $V_{OUT} = 9.0V$ $V_{OUT} = 13.5V$ $ I_{OUT} < 1\mu A$	5 10 15		1.5 3.0 4.0		2.25 4.50 6.75	l	_ _ _	1.5 3.0 4.0	
Input Current	"H"Level	I _{IH}	V _{IH} = 18V	18	_	0.1	_	10-5	0.1	_	1.0	μΑ
	"L" Level	I _{IL}	V _{IL} = 0V	18	_	- 0.1	_	- 10 ⁻⁵	-0.1	_	- 1.0	
Quiescent Current	Supply	I _{DD}	$V_{IN} = V_{SS}, V_{DD} *$	5 10 15		0.25 0.50 1.00		0.001 0.001 0.002	0.25 0.50 1.00		7.5 15.0 30.0	μΑ

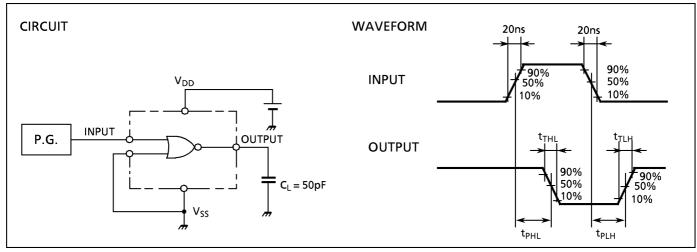
^{*} All valid input combinations.

2 2001-05-17

DYNAMIC ELECTRICAL CHARACTERISTICS (Ta = 25°C, Vss = 0V, $C_L = 50pF$)

CHARACTERISTIC	SYMBOL	TEST CONDITION	V _{DD} (V)	MIN.	TYP.	MAX.	UNIT
Output Transition Time	t _{TLH}		5 10 15	_ _ _	70 35 30	200 100 80	
Output Transition Time	t _{THL}		5 10 15	_ _ _	70 35 30	200 100 80	
Propagation Delay Time	t _{pLH}		5 10 15	_ _ _	65 30 25	200 100 80	ns
Propagation Delay Time	t _{pHL}		5 10 15		65 30 25	200 100 80	
Input Capacitance	C _{IN}		1	_	5	7.5	pF

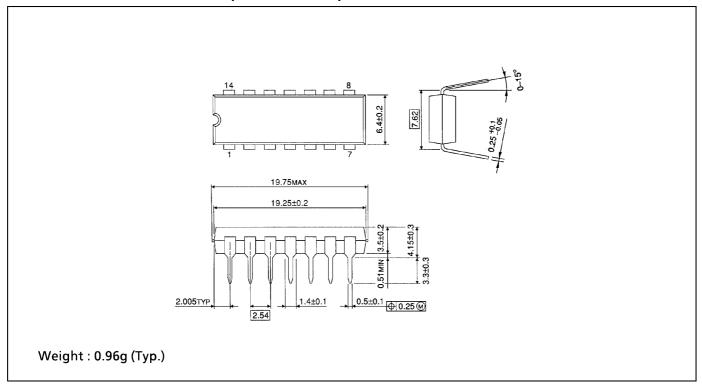
CIRCUIT A D WAVEFORM FOR MEASUREMENT OF DYNAMIC CHARACTERISTICS



3 2001-05-17

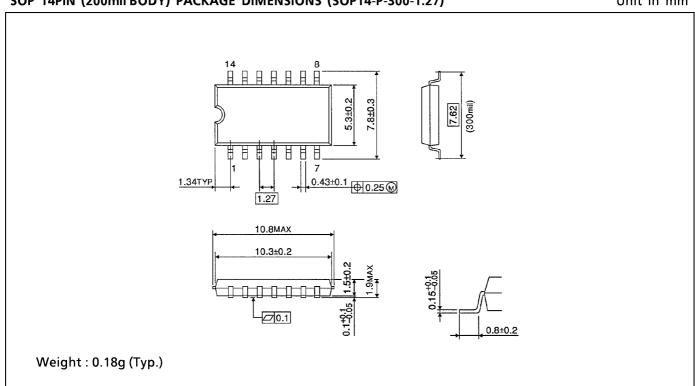
DIP 14PIN PACKAGE DIMENSIONS (DIP14-P-300-2.54)

Unit in mm



SOP 14PIN (200mil BODY) PACKAGE DIMENSIONS (SOP14-P-300-1.27)

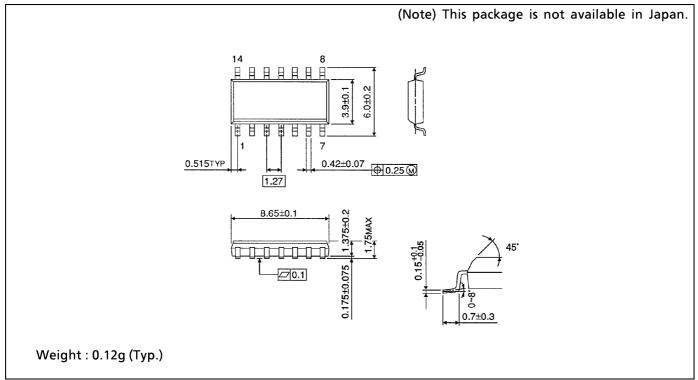
Unit in mm



4 2001-05-17

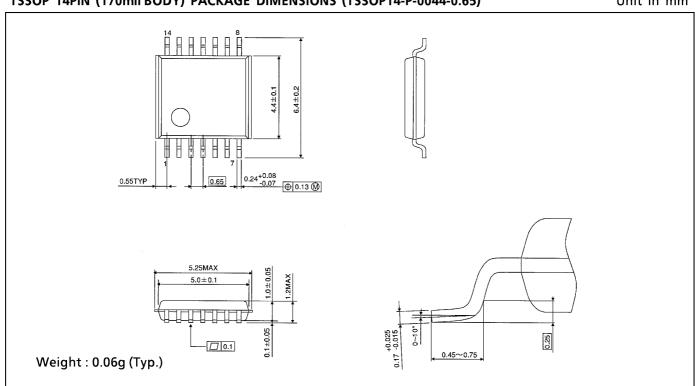
SOP 14PIN (150mil BODY) PACKAGE DIMENSIONS (SOL14-P-150 -1.27)

Unit in mm



TSSOP 14PIN (170mil BODY) PACKAGE DIMENSIONS (TSSOP14-P-0044-0.65)

Unit in mm



5

2001-05-17

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6 2001-05-17